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(54) Title: APPARATUS FOR TESTING INTEGRATED CIRCUITRY

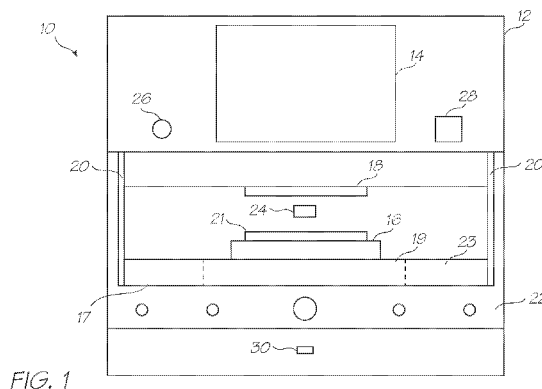


FIG. 1

(57) Abstract: A testing apparatus for testing integrated circuits mounted in a carrier includes a support assembly. A controller is mounted in the support assembly. The controller is programmed to process test signals from the integrated circuits. A retaining assembly is arranged on the support assembly and is configured to receive and retain the carrier during testing. A displacement mechanism is arranged on the support assembly for displacing the retaining assembly relative to the support assembly into and out of an operative condition. Testing circuitry is operatively connected to the controller and has at least test signal generation and measurement circuitry and adaptor circuitry for operative engagement with the integrated circuits being tested, the adaptor circuitry being configured to provide both a physical and an electrical interface with the integrated circuits.

